



DESCRIPTION

The AM40T65 is available in TO-3PN package.

V _{CES}	I _C	V _{CE}	P _D
650V	40A	1.55V	333W

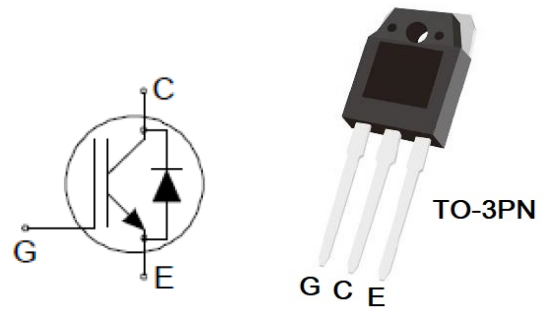
FEATURE

- Fast Switching
- Positive temperature coefficient
- Fast recovery anti-parallel diode

APPLICATION

- Welding converters
- UPS
- Air condition

PIN DESCRIPTION



ORDERING INFORMATION

Package Type	Part Number	
TO-3PN SPQ: 30pcs/Tube	TX	AM40T65TXU
		AM40T65TXVU
Note	U: Tube V: Halogen free Package	
AiT provides all RoHS products		

Pin#	Symbol	Function
1	G	Gate
2	C	Collector
3	E	Emitter

**ABSOLUTE MAXIMUM RATINGS** $T_C = 25^\circ\text{C}$, unless otherwise noted

V_{CES} , Collector-Emitter Voltage		650V
I_C , Collector Current	$T_C=25^\circ\text{C}$	80A
	$T_C=100^\circ\text{C}$	40A
I_{CM} , Pulsed Collector Current ⁽¹⁾	$T_C=25^\circ\text{C}$	120A
I_F , Diode Continuous Forward Current	$T_C=25^\circ\text{C}$	40A
	$T_C=100^\circ\text{C}$	20A
I_{FM} , Diode Maximum Forward Current	$T_C=25^\circ\text{C}$	80A
V_{GES} , Gate-Emitter Voltage		$\pm 30\text{V}$
P_D , Power Dissipation	$T_C=25^\circ\text{C}$	333W
T_{JMAX} , Operating Junction Temperature Range		+150°C
T_{STG} , Storage Temperature Range		-55°C~+175°C
T_L , Maximum Temperature for Soldering		270°C

Stress beyond above listed "Absolute Maximum Ratings" may lead permanent damage to the device. These are stress ratings only and operations of the device at these or any other conditions beyond those indicated in the operational sections of the specifications are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

*Pulse width limited by maximum junction temperature

THERMAL CHARACTERISTICS

Parameter	Symbol	Typ.	Max	Units
Junction-to-Case (IGBT)	$R_{\theta JC}$	-	0.45	°C/W
Junction-to-Case (Diode)	$R_{\theta JC}$	-	1.12	
Junction-to-Ambient	$R_{\theta JA}$	-	40	



ELECTRICAL CHARACTERISTICS

T_c = 25°C, unless otherwise stated.

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
OFF Characteristics						
Collector-Emitter Breakdown Voltage	V _{CE(S)}	V _{GE} =0V, I _C =-250μA	650	-	-	V
Collector-Emitter Leakage Current	I _{CE(S)}	V _{CE} = 650V, V _{GE} =0V	-	-	4	μA
Gate-Emitter Leakage Current	I _{GES(F)}	V _{GE} =+30V	-	-	200	nA
Gate-Emitter Reverse Leakage	I _{GES(R)}	V _{GE} =-30V	-	-	-200	
ON Characteristics						
Collector-Emitter Saturation Voltage	V _{CE(sat)}	V _{GE} =15V, I _C =40A	-	1.55	1.9	V
Gate Threshold Voltage	V _{GE(TH)}	V _{CE} =V _{GE} , I _C =1mA	4.8	5.5	6.2	
Pulse width tp≤300μs, δ≤2%						
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{CE} =25V, V _{GE} =0V, f=1.0MHz	-	2170	-	pF
Output Capacitance	C _{oss}		-	94	-	
Reverse Transfer Capacitance	C _{rss}		-	27	-	
Total Gate Charge	Q _g	I _C =40A, V _{CE} =520V, V _{GE} =15V	-	105	-	nC
Switching Characteristics						
Turn-on Delay Time	t _{d(on)}	I _C =40A, V _{CE} =400V, V _{GE} =15V, R _G =10Ω, T _J =25°C, Inductive Load	-	30	-	ns
Rise Time	t _r		-	65	-	
Turn-Off Delay Time	t _{d(off)}		-	165	-	
Fall Time	t _f		-	23	-	
Turn-On Switching Loss	E _{on}		-	1.24	-	mJ
Turn-Off Switching Loss	E _{off}		-	0.75	-	
Total Switching Loss	E _{ts}		-	1.99	-	
Diode Characteristics						
Diode Forward Voltage	V _F	I _F =20A	-	1.95	2.4	V
Reverse Recovery Time	T _{rr}	I _F =20A,	-	112	-	ns
Reverse Recovery Charge	Q _{rr}	di/dt=200A/us,	-	650	-	nC
Reverse Recovery Current	I _{rrm}	T _J =25°C	-	10.0	-	A



TYPICAL PERFORMANCE CHARACTERISTICS

Fig 1. Forward Bias Safe Operating Area

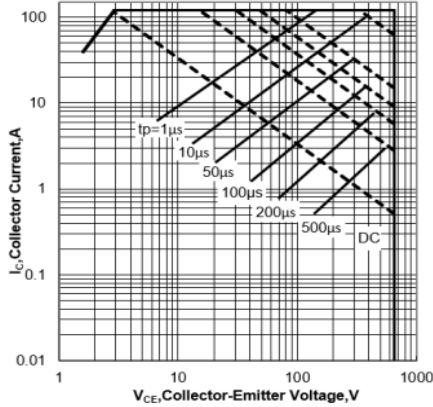


Fig 2. Power Dissipation vs. Case Temperature

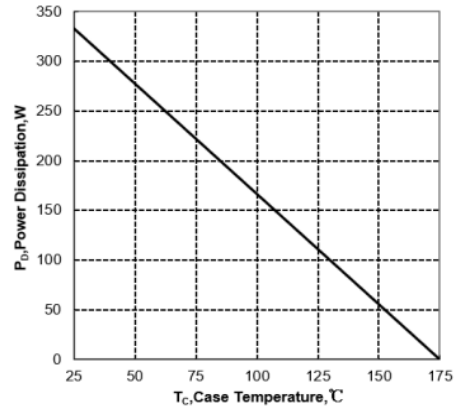


Fig3. Collector Current vs. Case Temperature

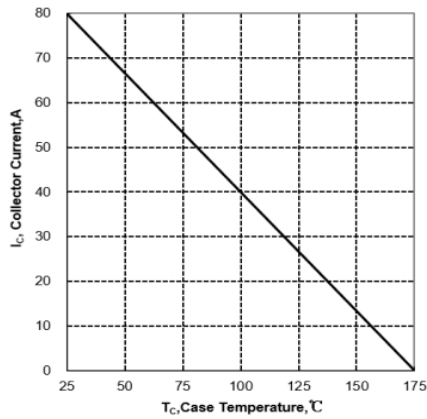


Fig4. Typical Transfer Characteristics

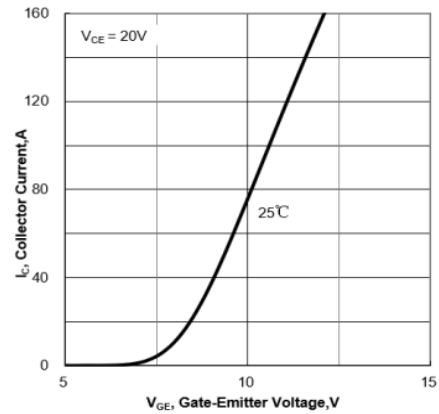


Fig5. Typical Output Characteristics ($T_C = 25^{\circ}$ C)

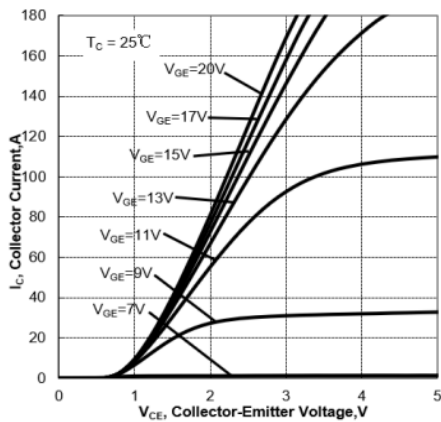


Fig6. Typical Gate Charge

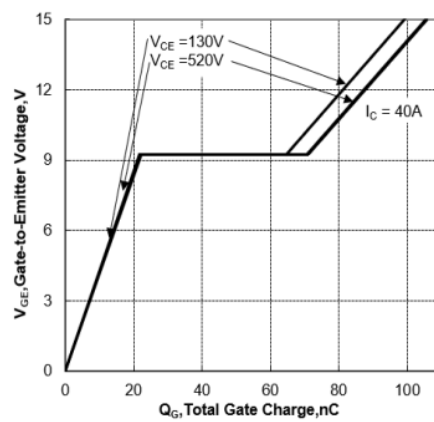




Fig7. Typical Capacitance vs. Collector-Emitter Voltage

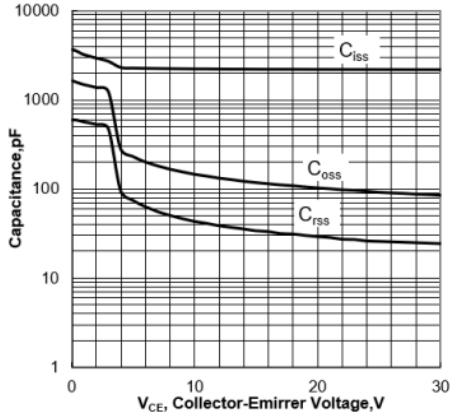


Fig8. IGBT Transient Thermal Impedance vs. Pulse Width

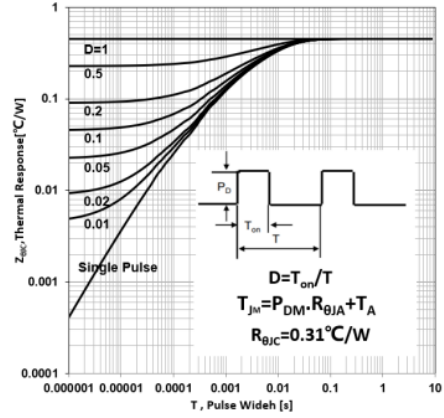


Fig9. Diode Transient Thermal Impedance vs. Pulse Width

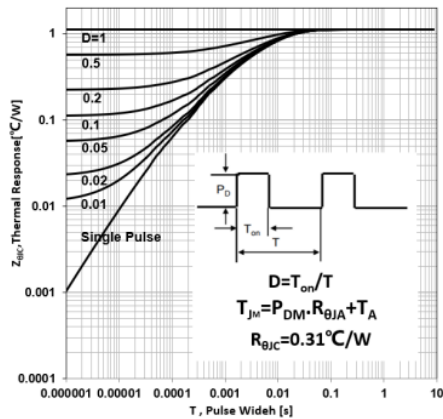


Fig10. Typical Diode Forward Current vs. Forward Voltage

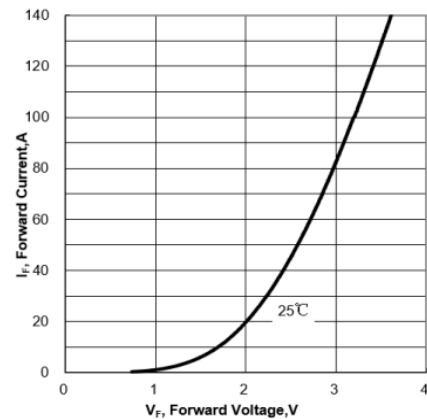


Fig11. Inductive Switching Test Circuit

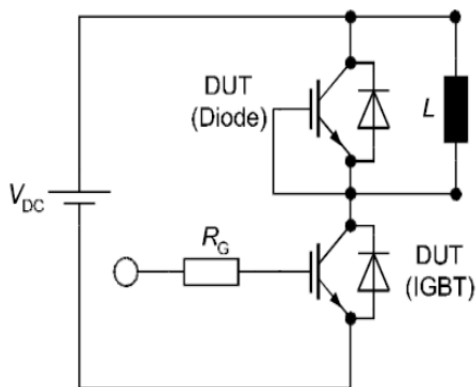


Fig12. Definition of Switching Times

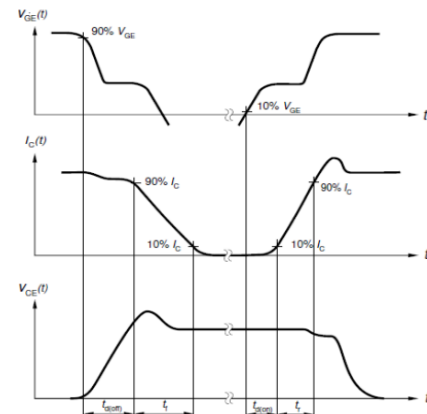




Fig13. Definition of Switching Losses

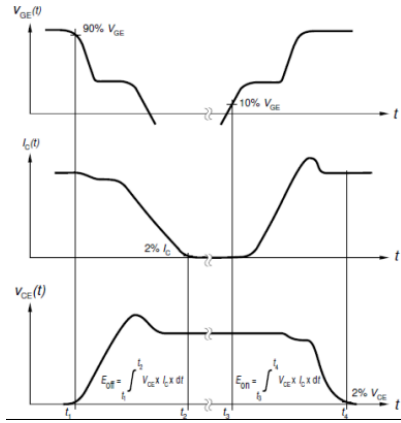
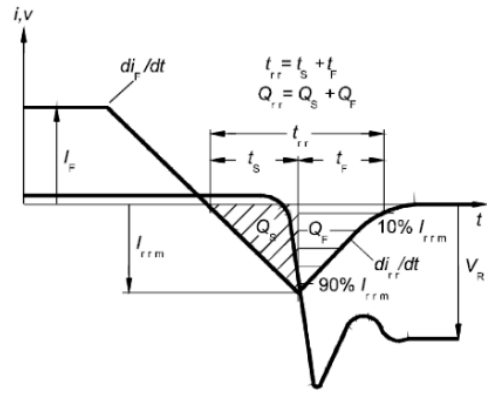


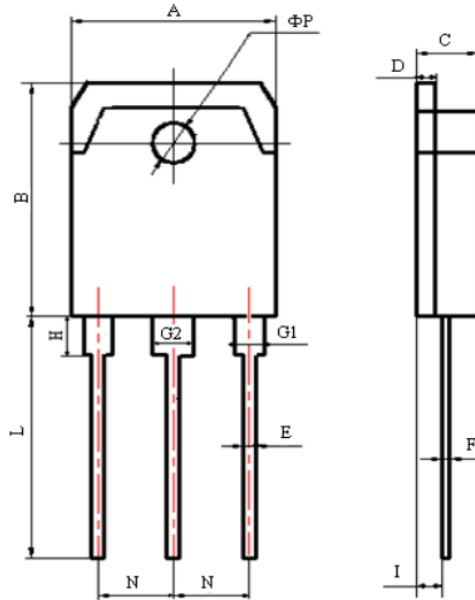
Fig14. Definition of Diode Switching Characteristics





PACKAGE INFORMATION

Dimension in TO-3PN (Unit: mm)



Symbol	Min.	Max.
A	15.000	16.000
B	19.200	20.600
C	4.600	5.000
D	1.400	1.600
E	0.900	1.100
F	0.500	0.700
G1	2.000	2.200
G2	3.000	3.200
H	3.000	3.700
I	1.200	2.900
L	19.000	21.000
N	5.250	5.650
ΦP	3.100	3.300



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